PATENT

1 4/14 1

. 15.

Docket No.: 1743/227

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS

Hideo TODOKORO, et al.

SERIAL NO.

(Cont. of 09/486,042)

FILED

(Herewith)

FOR

SCANNING ELECTRON MICROSCOPE

GROUP ART UNIT:

2881 (Anticipated)

Examiner

K. T. Nguyen (Anticipated)

COMMISSIONER FOR PATENTS P. O. Box 1450 Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97

SIR:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 in and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all of the references have already been considered by the Examiner in application number 09/486,042, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

Date: 04 November 2003

David J. Zibell

(Reg. No. 36,394)

KENYON & KENYON 1500 K Street, N.W., Suite 700 Washington, D.C. 20005-1257

(202) 220-4200 (phone) (202) 220-4201 (fax)

DC01 474366 v 1

Sheet 1 of 1 **FORM PTO-1449** INFORMATION DISCLOSURE Atty Docket No. : 1743/227 STATEMENT BY APPLICANT(S) Serial No. Inventors : H. Todokoro et al. Filed Group Art Unit : 2881 (Anticipated) Examiner : K.T. Nguyen (Anticipated) **U.S. PATENT DOCUMENTS** Patent Patent Examiner Class/ Filing Initial Number Date Name Subclass Date 5,872,358 02/16/99 TODOKORO et al. 250/310 6,025,593 02/15/00 SUZUKI et al. 250/310 4,922,097 TODOKORO et al. 250/310 05/01/90 5,517,028 05/14/96 ITO et al. 250/310 6,037,589 03/14/00 YONEZAWA et al. 250/310 5,389,787 02/14/95 TODOKORO et al. 5,424,541 TODOKORO et al. 06/23/95 5,608,218 03/04/97 SATO et al. FOREIGN PATENT DOCUMENTS Translation Examiner Document Class/ Initial Yes No Number Date Country Subclass 59-001916 01/11/84 ABS. Japan ABS. 60-061238 03/26/85 Japan 06/30/97 Japan X 9-171791 Χ 5-266855 10/15/93 Japan X 61-220259 09/30/86 Japan X 6-139985 05/20/94 Japan 7-192679 07/28/95 Japan 60-146439 08/02/85 Japan **EXAMINER** DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.